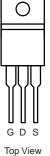


IRL7833PBF-VB Datasheet

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	30				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0. 0020				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0. 0028				
I _D (A)	140				
Configuration	Single				





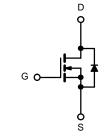
TO-220AB



- DT-Trench Power MOSFET
- ٠
- 100 % R_g and UIS Tested Compliant to RoHS Directive 2011/65/EU ٠

APPLICATIONS

- OR-ing
- Server ٠
- DC/DC •



N-Channel MOSFET

ABSOLUTE MAXIMUM RATING	S (T _A = 25 °C, unle	ess otherwise no	oted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		140 ^{a, e}	
Continuous Drain Current ($T_1 = 175 \ ^{\circ}C$)	T _C = 70 °C		110 ^e	
Commuted Brain Current $(T_J = 175 C)$	T _A = 25 °C	I _D	39 ^{b, c}	A
	T _A = 70 °C		28 ^{b, c}	
Pulsed Drain Current	I _{DM}	370		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39	
Single Pulse Avalanche Energy	L = 0.1 IIIA	E _{AS}	375	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C		90 ^{a, e}	А
	T _A = 25 °C	I _S	3.13 ^{b, c}	
Maximum Power Dissipation	T _C = 25 °C		250 ^a	
	T _C = 70 °C	PD	175	14/
	T _A = 25 °C	FD -	3.75 ^{b, c}	W
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10$ sec	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	- C/W	

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

a. t = 10 sec.
d. Maximum under steady state conditions is 90 °C/W.
e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-,					
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current		$V_{DS} = 30 V V_{GS} = 0 V$			1	<u> </u>
	IDSS	$V_{DS} = 24 \text{ V } V_{GS} = 0 \text{ V}, \text{T}_{\text{J}} = 55 ^{\circ}\text{C}$			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			А
	_	V _{GS} = 10 V, I _D = 38.8 A		0.0020		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 37 \text{ A}$	0.0028			Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S
Dynamic ^b					<u> </u>	
Input Capacitance	C _{iss}			8400		pF
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1725		
Reverse Transfer Capacitance	C _{rss}			970		
Tatal Cata Channe	$V_{DS} = 15 V_{V} V_{CS} = 10 V_{V}$	V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 38.8 A		171	257	nC
Fotal Gate Charge Q _g	Qg			81.5	123	
Gate-Source Charge	Q _{gs}	V_{DS} = 15 V, V_{GS} = 4.5 V, I_{D} = 28.8 A		34		
Gate-Drain Charge	Q _{gd}			29		
Gate Resistance	Rg	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	- ns
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17	
Turn-Off Delay Time	t _{d(off)}	$I_{D}\cong$ 24 A, V_{GEN} = 10 V, R_{g} = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.67 Ω		180	270	
Turn-Off Delay Time	t _{d(off)}	$\rm I_D \cong 22.5$ A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C		140		Δ
Pulse Diode Forward Current ^a	I _{SM}			370		A
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 20 A, di/dt = 100 A/μs, Τ _J = 25 °C		70.2	105	nC
Reverse Recovery Fall Time	t _a	$r_F = 20 \text{ A}, \text{ and } r = 100 \text{ A/} \mu\text{s}, r_J = 25 ^{\circ}\text{C}$		27		~~
Reverse Recovery Rise Time	t _b			25		ns

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

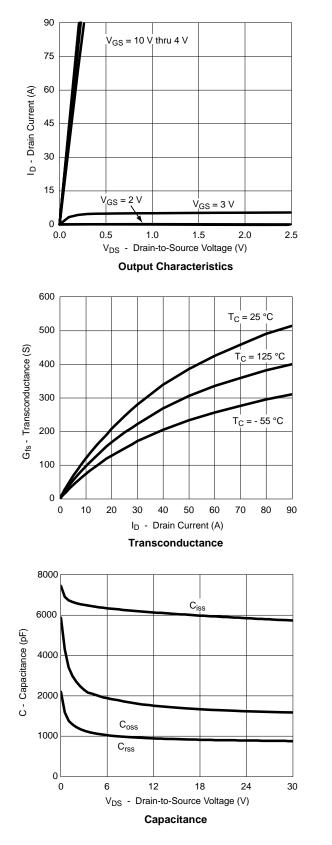
b. Guaranteed by design, not subject to production testing.

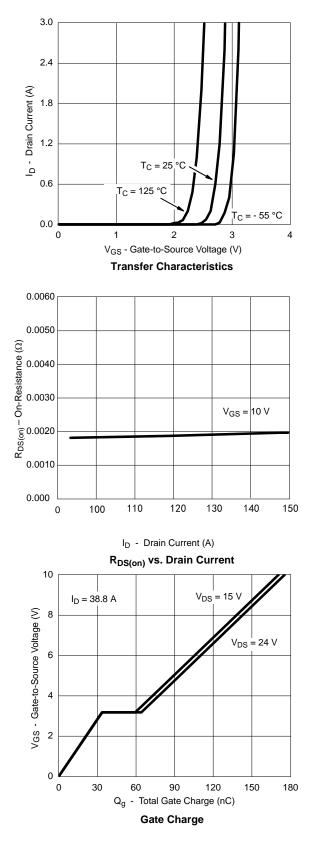
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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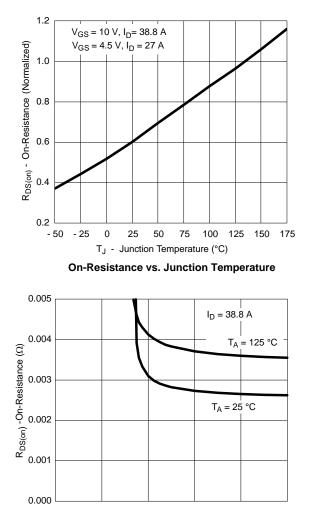


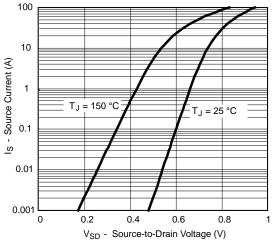


服务热线:400-655-8788

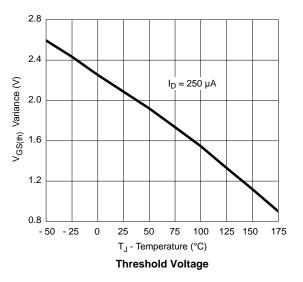


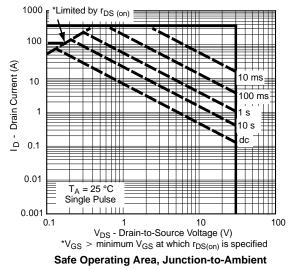
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Forward Diode Voltage vs. Temperature





0

2

4

6

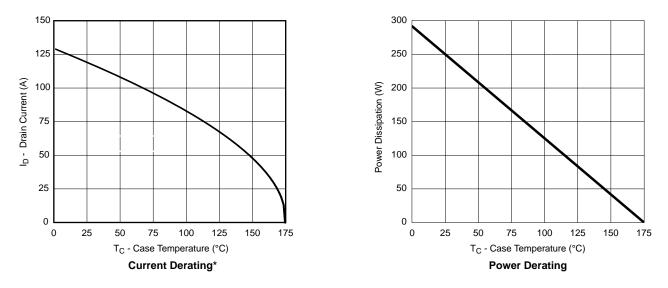
 V_{GS} - Gate-to-Source Voltage (V)

R_{DS(on)} vs. V_{GS} vs. Temperature

8

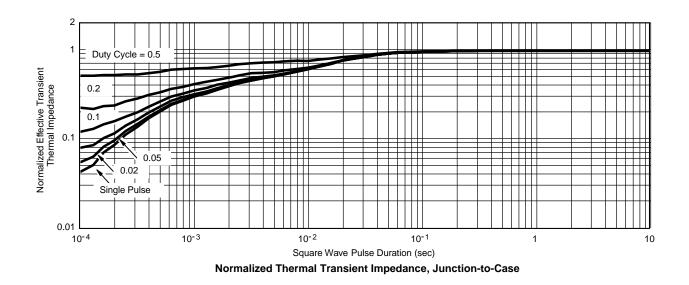
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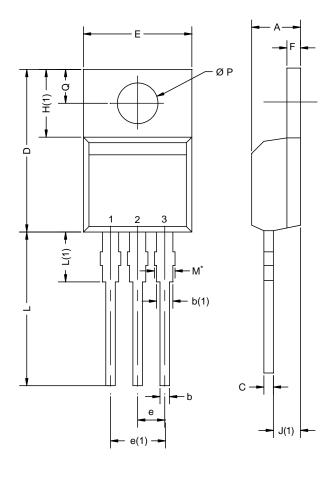
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-220AB



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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